Docket No.: 58799-03





IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Atsushi OGINO, et al.

Serial No.:

Group Art Unit:

Filed: February 13, 2001

Examiner

For: A

A METHOD OF PROVIDING LOCATION SERVICE USING CDMA-BASED CELLULAR PHONE SYSTEM, A METHOD OF MEASURING LOCATION AND

LOCATION SYSTEM

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents Washington, DC 20231

Dear Sir

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

The non-English language reference is accompanied by an English abstract.

Respectfully submitted,

MCDERMOTT, WILL & EMERY

Michael E. Fogarty Registration No. 36,139

600 13th Street, N.W.

Washington, DC 20005-3096

(202) 756-8000 MEF:dtb Date: February 13, 2001

FacsimaleL (2027 SRED) CES CONSIDERED EXCEPT WHERE LINED THROUGH. /H.P./

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